

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.

584-28418-US

SERIAL NO.

10/674,204

APPLICANT

Michael A. Frenkel et al.

FILING DATE

September 29, 2003

GROUP / CONFIRMATION

N/A / 2667

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TL	AA	5,452,761	09/26/95	Beard et al.	166	250	10/31/94
TL	AB	5,889,729	03/30/99	Frenkel et al.	367	73	09/30/96
TL	AC	6,060,885	05/09/00	Tabarovsky et al.	324	366	06/13/97
TL	AD	6,219,619	04/17/01	Xiao et al.	702	7	03/08/99
TL	AE	6,381,542	04/30/02	Zhang et al.	702	7	04/05/00
TL	AF	6,442,488	08/27/02	Xiao et al.	702	9	03/01/01
	AG						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBL. DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO	
	AH							
	AI							
	AJ							

OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages of Publication, Etc.)

TL	AK	Victor Rosato et al.; <i>Real Time Interpretation of MWD Anisotropy in High Angle Wells, Offshore Gulf of Mexico</i> , SPWLA 38th Annual Logging Symposium, June 15-18, 1997, pp. 1-6, 8 Figs., 1 Table.
TL	AL	T. Hagiwara et al.; <i>Identifying and Quantifying Resistivity Anisotropy in Vertical Boreholes</i> , SPWLA 40th Annual Logging Symposium, May 30-June 3, 1999, pp. 1-11, 13 Figs., 1 Table.
TL	AM	R. Griffiths et al.; <i>Optimal Evaluation of Formation Resistivities Using Array Induction and Array Laterolog Tools</i> , SPWLA 41st Annual Logging Symposium, June 4-7, 2000, pp. 1-13, 23 Figs.

EXAMINER

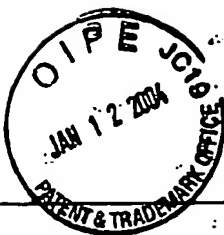
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Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next comment to applicant



FORM - 1449

SHEET 2

OF 2

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	BA						
	BB						
	BC						
	BD						
	BE						
	BF						
	BG						

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	BH							
	BI							
	BJ							

OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages of Publication, Etc.)

TL	BK	Wei Yang, <i>Determining Resistivity Anisotropy By Joint Lateral And Induction Logs</i> , SPWLA 42nd Annual Logging Symposium, June 17-20, 2001, pp. 1-5, 10 Figs.
TL	BL	K. S. Kunz et al.; <i>Some Effects of Formation Anisotropy on Resistivity Measurements in Boreholes</i> , Geophysics, V. 34, No. 4, October pp 770-794, 10 Figs.
TL	BM	Michael A. Frenkel et al.; <i>Real-time Estimation of Resistivity Anisotropy Using Array Lateral and Induction Logs</i> , OTC 15125, 2003 Offshore Technology Conference, Houston, Texas, 5-8 May, 2003, pp. 1-6, 2 Figs.

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SHEET 1

OF 2

SUPPLEMENTAL
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TL	AH	GB2368915A	15.05.02	UK			X	
TL	AI	WO95/03557	02.02.95	WIPO			X	
	AJ							

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	AL	
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